Edge AI for Wearables and IoT

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Message from the Guest Editor

Next generation technologies will utilize existing and emerging wearables and the Internet of Things (IoT) to continuously collect heterogeneous signals and data from unsupervised settings and apply real-time signal processing and artificial intelligence (AI) embedded into edge computing devices to seamlessly generate meaningful interpretations and actionable decisions. Rapid progress in embedded technologies with high computing power and ubiquitous connectivity using Bluetooth, Wi-Fi, and 5G along with miniature, low-cost, flexible, and reliable sensors have paved the hardware revolution for these technologies. The purpose of this Special Issue is to address the ongoing research activities in these fields of wearables and IoT with focus on edge AI for a variety of applications including biomedical, mobile health, smart health, smart cities, environmental, remote monitoring, robotics, assistive technologies, and elderly monitoring applications.

For more details, please visit here.

Special Issue

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Message from the Editor-in-Chief

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